Search Notes	Application/Control No. 10574402	Applicant(s)/Patent Under Reexamination RIEDER ET AL.
[barcode]	Examiner DAVID S BAKER	Art Unit 2884

SEARCHED

Class	Subclass	Date	Examiner
250	338.1	12 FEB 09	/DSB/
250	339.11	12 FEB 09	/DSB/
250	339.14	12 FEB 09	/DSB/
250	341.8	12 FEB 09	/DSB/
250	342	12 FEB 09	/DSB/
250	339.02	12 FEB 09	/DSB/
250	349	12 FEB 09	/DSB/

SEARCH NOTES

Search Notes	Date	Examiner
See attached EAST Search History	12 FEB 09	/DSB/
Consultation: Examiner Christine Sung AU 2884	07 DEC 08	/DSB/
Consultation: Examiner Constantine Hannaher AU 2884	12 FEB 09	/DSB/

INTERFERENCE SEARCH

Class	Subclass	Date	Examiner
ALL	ALL; Seach Terms: "(infra$red OR IR).clm. AND (matrix OR array OR grid).clm. AND maximum.clm. AND comparator.clm. diode.clm."	12 FEB 09	/DSB/
250	ALL; Seach Terms: "(infra$red OR IR).clm. AND (matrix OR array OR grid).clm. AND maximum.clm. AND comparator.clm. diode.clm."	12 FEB 09	/DSB/
ALL	ALL; Search Terms: "(infra$red OR IR).clm. AND (matrix OR array OR grid).clm. AND maximum.clm. AND diode.clm."	12 FEB 09	/DSB/
250	ALL; Search Terms: "(infra$red OR IR).clm. AND (matrix OR array OR grid).clm. AND maximum.clm. AND diode.clm."	12 FEB 09	/DSB/
ALL	ALL; Search Terms: "(IR OR infra$red OR thermal).clm. AND (matrix OR array).clm. AND (maximum OR max OR strong$4 OR peak).clm. AND threshold.clm. AND comparator.clm. AND diode.clm."	12 FEB 009	/DSB/

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INTERFERENCE SEARCH

Class	Subclass	Date	Examiner
250	ALL; Search Terms: "(IR OR infra$red OR thermal).clm. AND (matrix OR array).clm. AND (maximum OR max OR strong$4 OR peak).clm. AND threshold.clm. AND comparator.clm. AND diode.clm."	12 FEB 09	/DSB/

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